



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**IN RE APPLICATION OF: Yukio HOSAKA, et al.**

**SERIAL NO: 10/820,123**

**GAU: 3723**

**FILED: April 8, 2004**

**EXAMINER:**

**FOR: ABRASIVE PAD, METHOD AND METAL MOLD FOR MANUFACTURING THE SAME, AND SEMICONDUCTOR WAFER POLISHING METHOD**

**INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97**

**COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313**

**SIR:**

Applicant(s) wish to disclose the following information.

**REFERENCES**

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**RELATED CASES**

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**CERTIFICATION**

- Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

**DEPOSIT ACCOUNT**

- Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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THE SAME, AND SEMICONDUCTOR WAFER POLISHING METHOD**STATEMENT OF RELEVANCY****References AO, AP and AQ on Form PTO-1449 are discussed in the specification.**

JUL 07 2004



SHEET OF

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251598US0	TRADEMARK OFFICE		SERIAL NO. 10/820,123
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Yukio HOSAKA, et al.					
		FILING DATE April 8, 2004		GROUP 3723			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA							
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
AM							
AN							
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
YES	NO						
AO	9-7985	01/10/1997	JAPAN (with English Abstract)				X
AP	2000-326220	11/28/2000	JAPAN (with English Abstract)				X
AQ	11-512977	11/09/1999	JAPAN (with English Abstract of corr. WO 97/06921)				X
AR	WO 97/06921	02/27/1997	WIPO (submitting English Abstract only)				
AS							
AT							
AU							
AV							
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner		Date Considered					

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.